

Special Issue

Artificial Intelligence in Fault Diagnosis and Signal Processing, 2nd Edition

Message from the Guest Editors

The early detection and diagnosis of faults is essential in industrial processes since it can help avoid potentially irreparable damage to machinery. Additionally, in terms of industrial safety, timely fault detection and diagnosis can facilitate safer operations, reducing the risks to which plant workers are exposed. Therefore, detecting and diagnosing faults quickly and accurately can facilitate decision-making in a way that enables corrective actions to be taken to repair damaged components. In recent years, various machine fault detection techniques have emerged, and artificial intelligence and signal processing have become essential components thereof. However, this research field continues to generate new trends in terms of the methodologies related to multiple fault detection, novelty detection, data mining, development in hardware, etc. The goal of this Special Issue is to present ideas that are relevant to the field of fault diagnosis using artificial intelligence and signal processing.

- neural networks
- machine learning
- sensors
- novelty detection
- data mining
- signal processing methods
- signal processing implementation
- FPGA
- HIL



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



mdpi.com/si/247292

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

[mdpi.com/journal/
applsci](https://mdpi.com/journal/applsci)



Guest Editors

Dr. Juan Jose Saucedo-Dorantes

Engineering Faculty, Autonomous University of Queretaro (UAQ), San Juan del Rio 76806, Mexico

Dr. David Alejandro Elvira-Ortiz

Engineering Faculty, Autonomous University of Queretaro (UAQ), San Juan del Rio 76806, Mexico

Deadline for manuscript submissions

closed (20 January 2026)



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



[mdpi.com/journal/
applsci](http://mdpi.com/journal/applsci)

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

